

**SLOVENSKI STANDARD  
SIST EN 60512-16-7:2008****01-december-2008**

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**Konektorji za elektronsko opremo - Preskusi in meritve - 16-7. del: Mehanski preskusi na kontaktih in priključkih - Preskus 16g: Merjenje deformacije kontakta po stiskanju (IEC 60512-16-7:2008)**

Connectors for electronic equipment - Tests and measurements - Part 16-7: Mechanical tests on contacts and terminations - Test 16g: Measurement of contact deformation after crimping (IEC 60512-16-7:2008)

Steckverbinder für elektronische Einrichtungen - Mess- und Prüfverfahren - Teil 16-7: Mechanische Prüfungen an Kontakten und Anschlüssen - Prüfung 16g: Kontaktverformung nach dem Crimpen (IEC 60512-16-7:2008)

Connecteurs pour équipements électroniques - Essais et mesures - Partie 16-7: Essais mécaniques des contacts et des sorties - Essai 16g: Mesure de la déformation d'un contact après sertissage (CEI 60512-16-7:2008)

**Ta slovenski standard je istoveten z: EN 60512-16-7:2008**

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**ICS:**

19.060	Mehansko preskušanje	Mechanical testing
31.220.10	Vtiči in vtičnice, konektorji	Plug-and-socket devices. Connectors

**SIST EN 60512-16-7:2008****en,fr**

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SIST EN 60512-16-7:2008

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EUROPEAN STANDARD  
NORME EUROPÉENNE  
EUROPÄISCHE NORM

**EN 60512-16-7**

September 2008

ICS 31.220.10

English version

**Connectors for electronic equipment -  
Tests and measurements -  
Part 16-7: Mechanical tests on contacts and terminations -  
Test 16g: Measurement of contact deformation after crimping  
(IEC 60512-16-7:2008)**

Connecteurs  
pour équipements électroniques -  
Essais et mesures -  
Partie 16-7: Essais mécaniques  
des contacts et des sorties -  
Essai 16g: Mesure de la déformation  
d'un contact après sertissage  
(CEI 60512-16-7:2008)

Steckverbinder  
für elektronische Einrichtungen -  
Mess- und Prüfverfahren -  
Teil 16-7: Mechanische Prüfungen  
an Kontakten und Anschlüssen -  
Prüfung 16g: Kontaktverformung  
nach dem Crimpen  
(IEC 60512-16-7:2008)

SIST EN 60512-16-7:2008

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Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

**CENELEC**

European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**Central Secretariat: rue de Stassart 35, B - 1050 Brussels**

## Foreword

The text of document 48B/1888/FDIS, future edition 1 of IEC 60512-16-7, prepared by SC 48B, Connectors, of IEC TC 48, Electromechanical components and mechanical structures for electronic equipment, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60512-16-7 on 2008-08-01.

This standard is to be read in conjunction with EN 60512-1 and EN 60512-1-100 which explains the structure of the EN 60512 series.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2009-05-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2011-08-01

Annex ZA has been added by CENELEC.

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## Endorsement notice

The text of the International Standard IEC 60512-16-7:2008 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 60352-2      NOTE Harmonized as EN 60352-2:2006 (not modified).  
<https://standards.iteh.ai/catalog/standards/sist/3d816074-a2cc-4bc4-8859-5db0271fb5b0/sist-en-60512-16-7-2008>

## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60512-1-1	- <sup>1)</sup>	Connectors for electronic equipment - Tests and measurements - Part 1-1: General examination - Test 1a: Visual examination	EN 60512-1-1	2002 <sup>2)</sup>

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<sup>1)</sup> Undated reference.

<sup>2)</sup> Valid edition at date of issue.

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IEC 60512-16-7

Edition 1.0 2008-07

# INTERNATIONAL STANDARD

## NORME INTERNATIONALE

**Connectors for electronic equipment – Tests and measurements –  
Part 16-7: Mechanical tests on contacts and terminations – Test 16g:  
Measurement of contact deformation after crimping**

**Connecteurs pour équipements électroniques – Essais et mesures –  
Partie 16-7: Essais mécaniques des contacts et des sorties – Essai 16g: Mesure  
de la déformation d'un contact après sertissage**

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

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**CONNECTORS FOR ELECTRONIC EQUIPMENT –  
TESTS AND MEASUREMENTS –**
**Part 16-7: Mechanical tests on contacts and terminations –  
Test 16g: Measurement of contact deformation after crimping**

## FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 60512-16-7 has been prepared by subcommittee 48B: Connectors, of IEC technical committee 48: Electromechanical components and mechanical structures for electronic equipment.

This standard cancels and replaces test 16g of IEC 60512-8, issued in 1993. This standard is to be read in conjunction with IEC 60512-1 and IEC 60512-1-100 which explains the structure of the IEC 60512 series.

The text of this standard is based on the following documents:

FDIS	Report on voting
48B/1888/FDIS	48B/1921/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.



This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 60512 series, under the general title *Connectors for electronic equipment – Tests and measurements*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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